



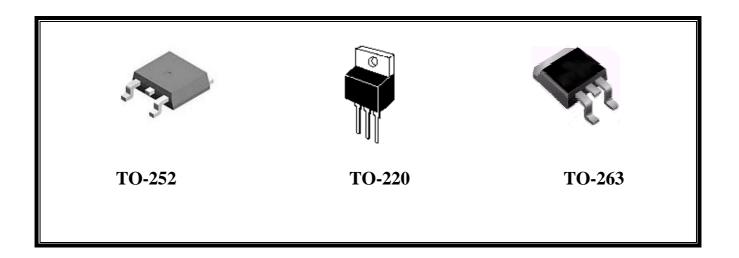
### DESCRIPTION

ET7805m The is fixed-voltage monolithic integrated-circuit voltage regulator, which is designed for a wide range of applications. These applications include on-card regulation for elimination of noise and distribution problems associated with single-point regulation. ET7805m can deliver up to 1.5 amperes of output current. The internal limiting and termal shutdown features of ET7805m make it essentially immune to overload.

The ET7805m is available in the plastic TO-252, TO-220 and TO-263 package.

#### FEATURE

- ➢ 3-Terminal Regulators
- Output Current Up to 1.5 A
- No External Components
- Internal Thermal Overload Protection
- High Power Dissipation Protection
- Internal Short-Circuit Current Limiting
- Output Transistor Safe-Area Compensation



# Absolute maximum ratings over operating temperature range (unless otherwise noted)

	ET 7805m	UNIT
Input voltage	35	V
Continuous total dissipation at 25°C free-air temperature	2	W
Continuous total dissipation at (or below) 25°C case temperature	15	
Operating free-air, case, or virtual junctions temperature range	0 to 150	
Storage temperature range	-65 to 150	°C
Lead temperature 1.6mm (1/16) from case for 10 seconds	260	



## **Recommended operating conditions**

PARAMETER	MIN	MAX	UNIT
Input voltage, V <sub>I</sub>	7	25	V
Output current, I <sub>O</sub>		1.5	А
Operating virtual junction temperature,	0	125	°C
TJ			

#### ET7805m electrical characteristics $V_I = 10V, I_O = 500mA$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS*		ET7805m			UNIT
			MIN	TYP	MAX	
		25℃	4.8	5	5.2	
Output voltage**	$I_0 = 5mA$ to 1A,	0°℃ to 125°℃	4.75	5	5.25	V
	$V_I = 8V$ to 21V, $P \leq 15W$					
Input regulation	$V_I = 8V$ to 25V	25℃		3	100	mV
	$V_I = 8V$ to $12V$			1	50	
Ripple rejection	$V_{I} = 8V$ to 18V, $f = 120Hz$	0°℃ to 125°℃	62	78		dB
Output regulation	$I_0 = 5mA$ to 1.5A	25℃		15	100	mV
	$I_0 = 250 \text{mA} \text{ to} 750 \text{mA}$			5	50	
Output resistance	f = 1 KHz	0°℃ to 125°℃		0.01		Ω
				7		
Temperature coefficient of	$I_O = 5mA$	0℃ to 125℃		-1.1		mV /℃
output voltage						
Output noise voltage	f = 10Hz to $100KHz$	<b>25℃</b>		40		μν
Dropout voltage	$I_O = 1A$	25℃		2.0		V
Bias current		25℃		4.2	8	
Bias current change	$V_{I} = 7V$ to $25V$	0°℃ to 125°℃			1.3	
	$I_0 = 5mA$ to $1A$				0.5	mA
Short-circuit output current		<b>25℃</b>		750		
Peak output current		25℃		2.2		А

\*Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately.

\*\* This specification applies only for dc power dissipation permitted by absolute maximum ratings.



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Test Report	No. 5H407126/CHEM	Dale: 4.26.2004	Page 1 of 2
	ELECTRONICS CHEMICALS CO., L CAD, JIANGQIAO INDUSTRIAL ZON		INA
The following sample(s	) was/were submitted and identified o	n behalf of the applan of	
Sample Description SGS Rei No.	: SY T810 ; SHEC0040402766-3		
Sample Receiving Date	: April 21, 2004		
Testing Period	: April 21 to April 26, 2004		
Test Requested	<ul> <li>1) To determine the Cadmium Cor</li> <li>2) To determine the Lead content of</li> <li>3) To determine Mercury Content of</li> <li>4) To determine Hexavalent Chron</li> <li>5) To determine the PBBs(Polybroid) (Polybrominated biphenyl ethers)</li> </ul>	if the submitted sample of the submitted sample, nium content of the submitt minated biphenyls) PBBEs	i¢u sample. (*8DEs)
Test method	<ol> <li>With reference to BS EN 1122:2 Analysis was performed by Indu Spectrometry (ICP-AES) or Ator</li> <li>With reference to US EPA Meth Analysis was performed by Indu Spectrometry (ICP-ACS) or Ator</li> <li>With reference to US EPA 3052 Analysis was performed by Indu Spectrometry (ICP-AES).</li> <li>With reference to US EPA3060/</li> <li>With reference to US EPA3060/</li> <li>With reference to US EPA 3081</li> </ol>	otively Coupled Argon Par nic Absorption Spediant of 3050B. ctively Coupled Argon Pla- nic Absorption Spectroard ctively Coupled Argon Pla- totely Coupled Argon Pla-	n . 1965 – Atomic Emission
Test Results	Please refer to next page		~

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Signed for and on behalf of SGS-CSTC Chemical Laboratory

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#### **Test Report** No. SH407126/CHEM Date: 4.26 (10) Page 2 of 2 Test Results 1) BS EN 1122:2001, Method B - Hoavy Metal Analysis : Cadmium Content A N.D. Cadmium (Cd) (Result shown is of the total weight of liquid sample) N.D. = Non-detected (Detection limit <2.0 ppm) 2) US EPA 3050B - Heavy Metal Analysis : Lead Contant Δ Lead (Pb) N.D. (Result shown is of the total weight of liquid sample) N.D. = Non-detected (Detection limit <2.0 ppm) 3) Mercury Content N.D. Mercury (Hg) (Result shown is of the lotal weight of liquid sample) N.D. = Non-detected (Detection limit <2.0 ppm) 4) Hexevelent Chromium Content Δ N.D. Hexavalent Chromium (Cr VI) (Result shown is of the total weight of liquid sample) N.D. = Non-detected (Detection limit <2.0 ppm) SteRe/Polybrominated binhenvis) PBBEs(PBDEs) (Polybrominated biphonyl off) at in patient

Test Ilem(s):	Δ
PBBs(Polybrominaled blphenyls)	N.D.
PBBEs(PBDEs)(Polybrominated biphenyl ethers)	N.O.

(Result shown is of the total weight of liquid sample) N.D. = Non detected (Detection limit <5.0 ppm)

Sample Description:

A. Transparent liquid

Note ppm=mg/kg

\*\*\* End of Report \*\*\*

this test Report is issued by the Company subject to be General Conditions of Service printed overlead to which et and Condition of the Service printed overlead to which et also evolve by equest or are eccessible at www.spa.com. Attention is drawn to the Instations of finbility, indexnel/leadors and jutisticulumat publicles dulivership way is results shown to the Test Roport antial only in the stronglets) tested unless often were stated and successcriptlet are strained for 20 days only. This test Report Model and the stronglet in Full, without approval of the Company.

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# QUALITY MANAGE SYSTEM CERTIFICATE OF CONFORMITY

This is to certify that the Quality Manage System of

Beijing Estek Electronics Co., Ltd.

(ADD: Rm 6A07 Changyin office building NO. 88 Yongding road Haidian district Beijing Postcode: 100039)

has been found to conform to Quality Manage System Standard:

## GB/T19001-2000-IS09001:2000

This quality manage system covers following product(s):Sales and services of integrated circuits and semiconductorsThe No. of this certificate is:2805Q10763R0SPromulgate Date:Jul.11.2005This certificate is valid until :Jul.10.2008(From Jul.12.2006,application efficiency with maintaining registration/certification)

Beijing Zhong-An-Zhi-Huan Certification Center (Former 8 • 1Centification Center of Quality System)

Center Director:

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ACCREDITED BY MEMBER OF THE INTERNATIONAL ACCREDITATION FORUM AND PACIFIC ACCREDITATION COOPERATION MULTILATERAL RECOGNITION ARRIANGEMENT FOR QUALITY MANAGEMENT SYSTEMS